

Evaluating architectural, redundancy, and implementation strategies for radiation hardening of FinFET integrated circuits
Pagliarini, Samuel Nascimento; Benites, Luis; Martins, Mayler; Rech, Paolo; Kastensmidt, Fernanda IEEE transactions on nuclear science 2021 / p. 1045-1053 <https://doi.org/10.1109/TNS.2021.3070643> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

A security-aware and LUT-based CAD flow for the physical synthesis of hASICs

Abideen, Zain Ul; Perez, Tiago Diadami; Martins, Mayler; **Pagliarini, Samuel Nascimento** IEEE transactions on computer-aided design of integrated circuits and systems 2023 / p. 3157-3170 : ill <https://doi.org/10.1109/TCAD.2023.3244879> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)